

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/604,114	THOMPSON ET AL.	
Examiner	Art Unit	
Tianjie Chen	2627	

SEARCHED					
Class	Subclass	Date	Examiner		
Updated		6/8/2006	ΤJ		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	